

METHOD FOR QUANTIFYING SAFE  
OPERATING AREA FOR BIPOLAR  
JUNCTION TRANSISTOR  
Inventors: Kim et al.  
Atty. Docket No. P05779

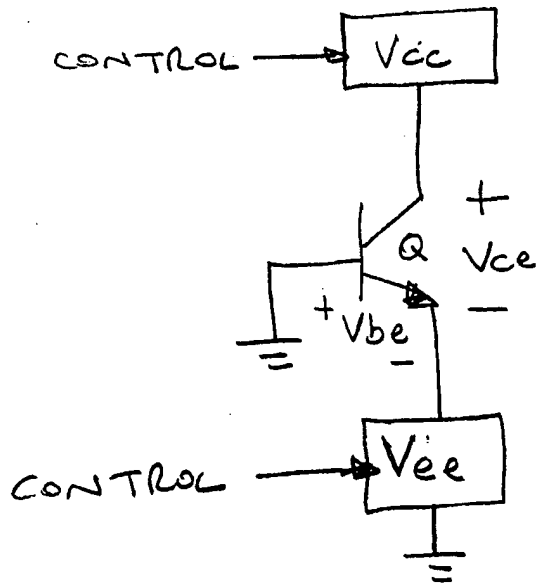


FIGURE 1A  
(PRIOR ART)

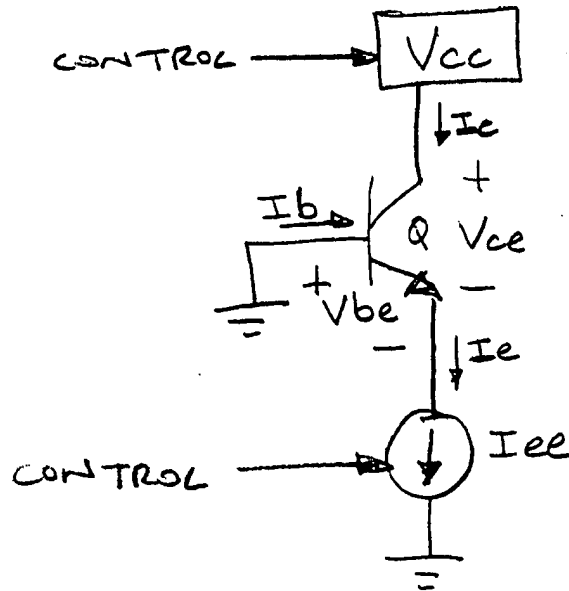


FIGURE 2A  
(PRIOR ART)

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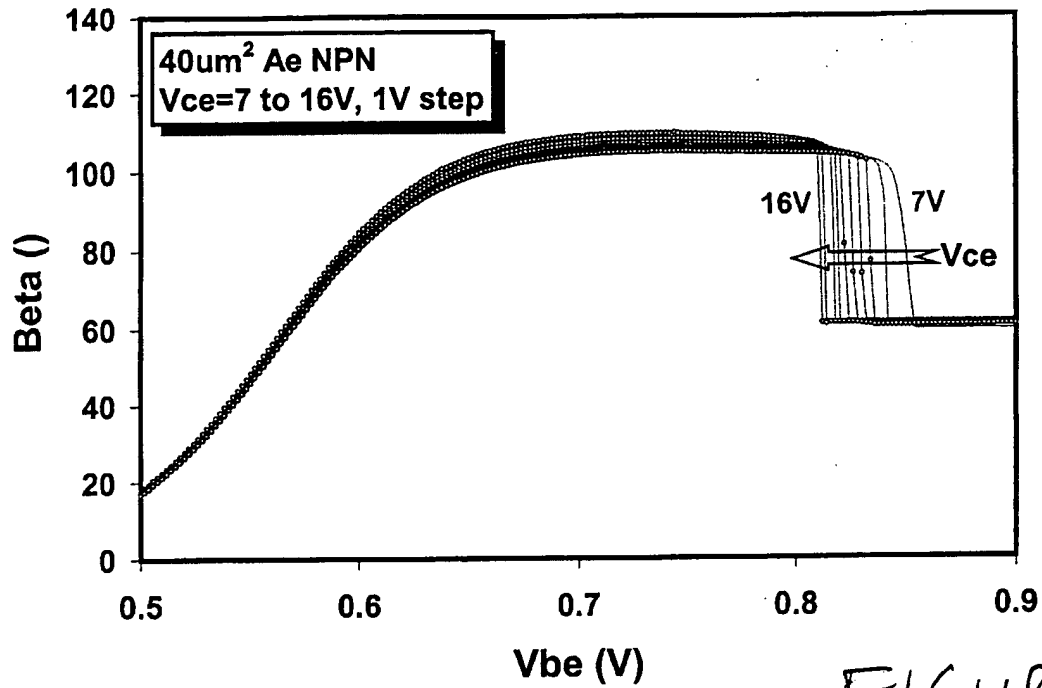


FIGURE 1B  
(PRIOR ART)

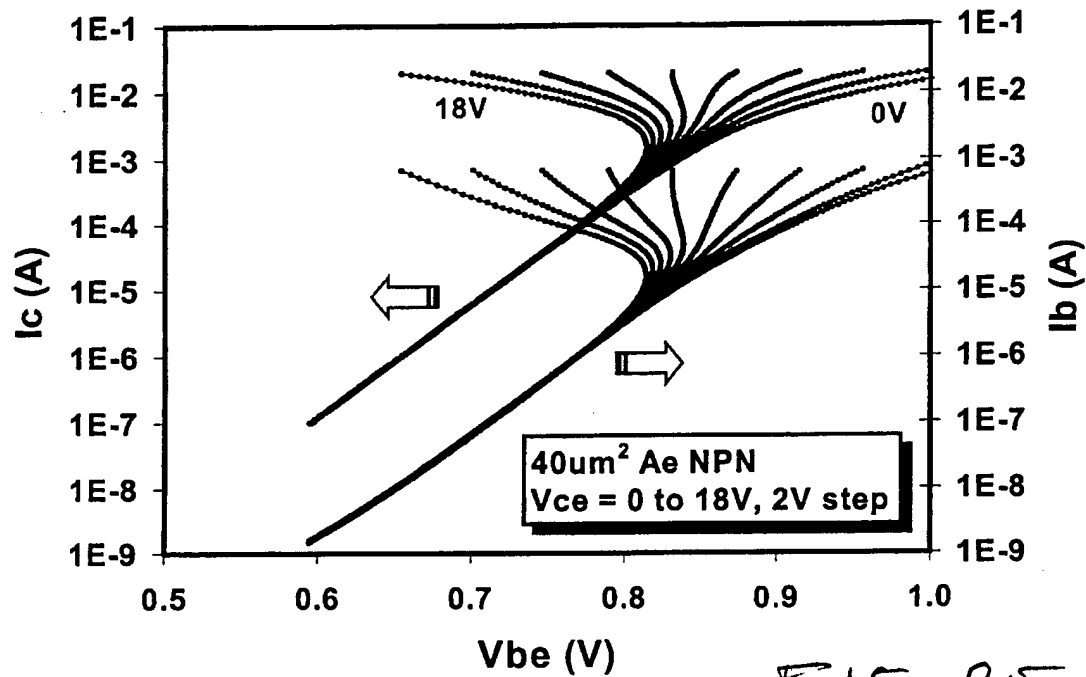


FIGURE 2B  
(PRIOR ART)

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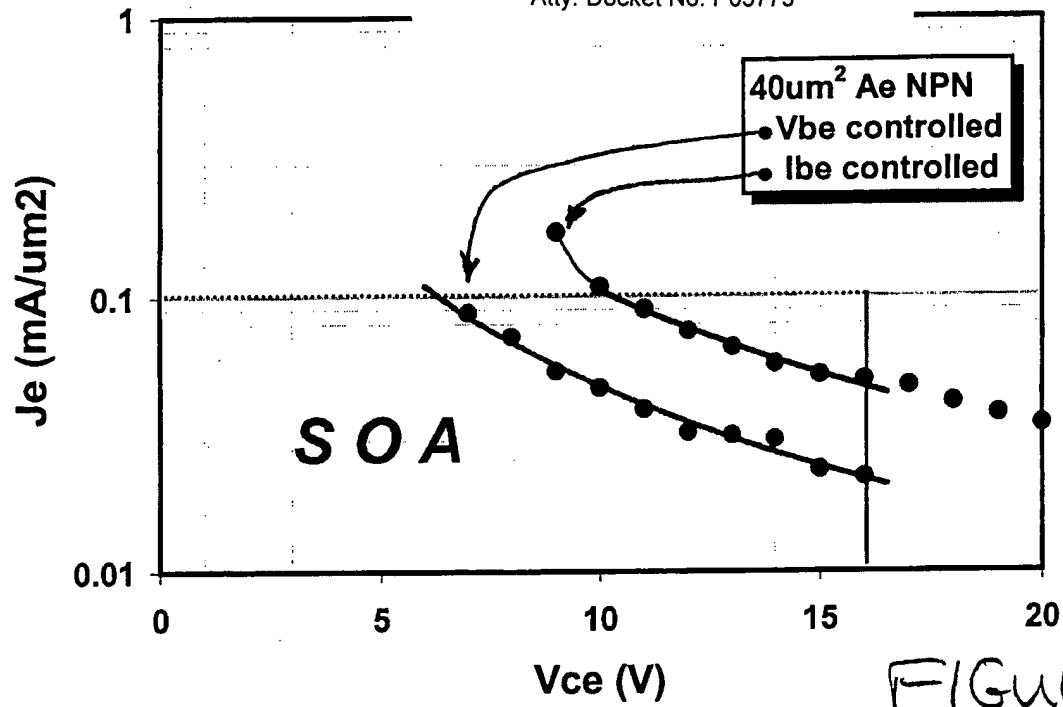


FIGURE 3  
(PRIOR ART)

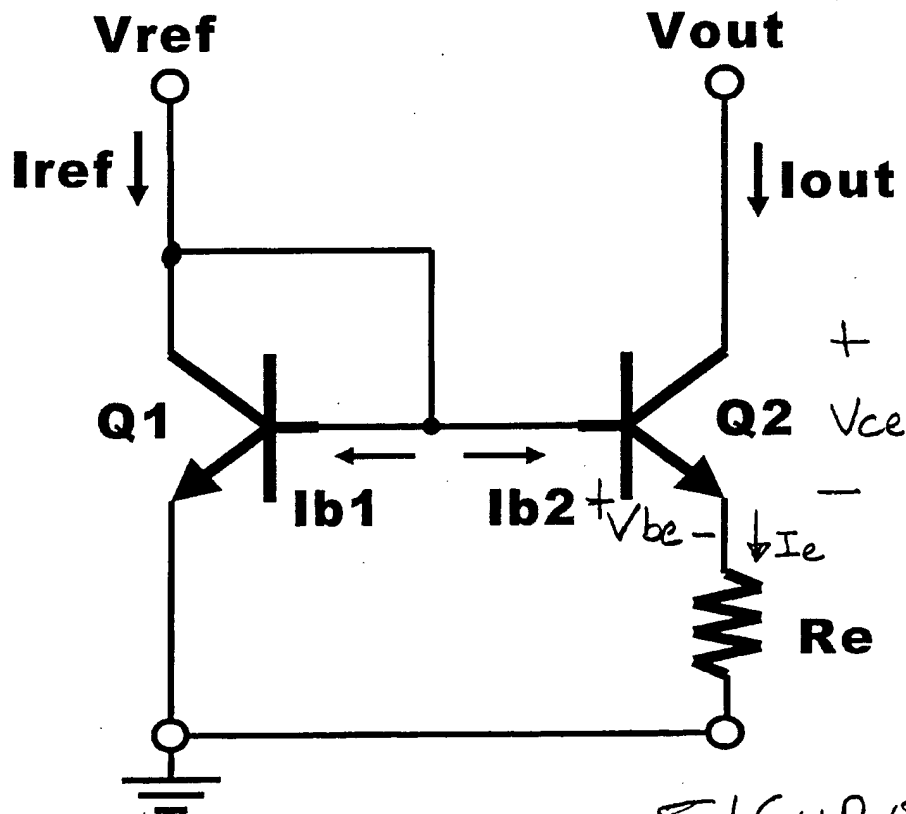
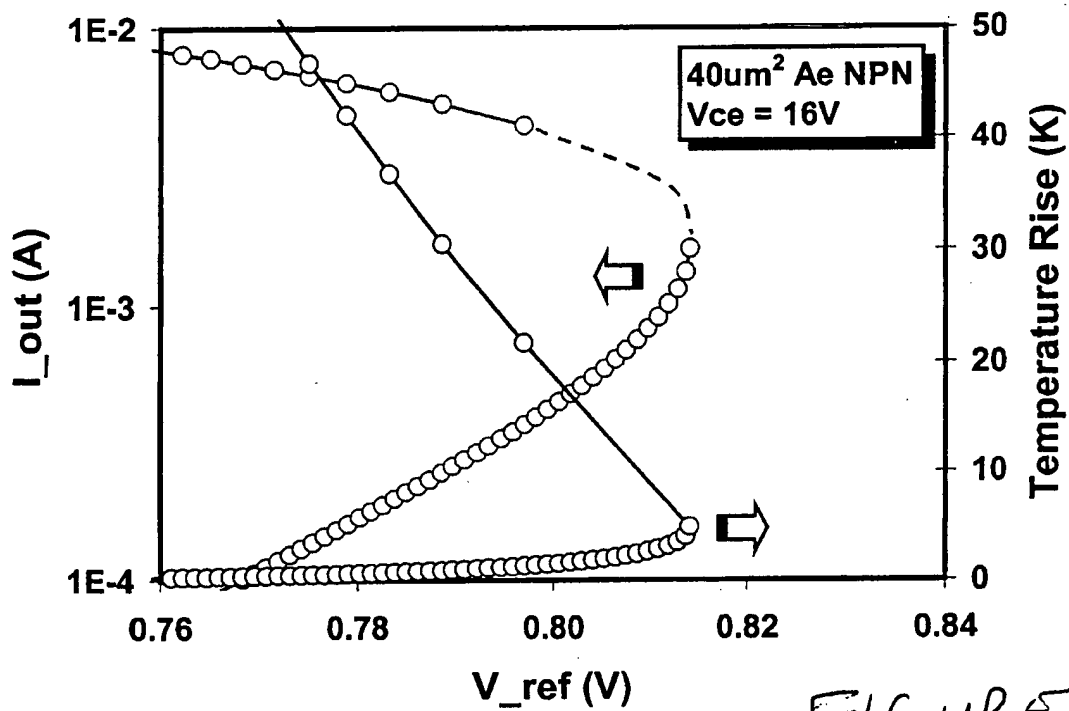
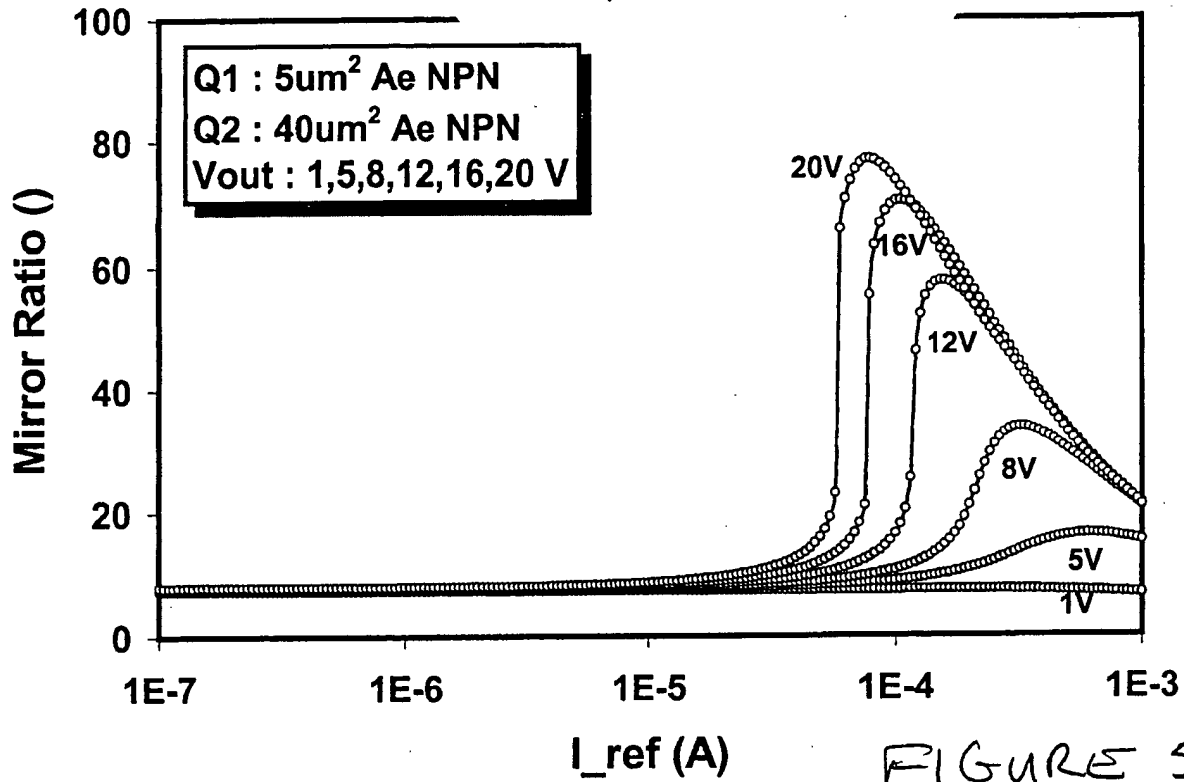


FIGURE 4

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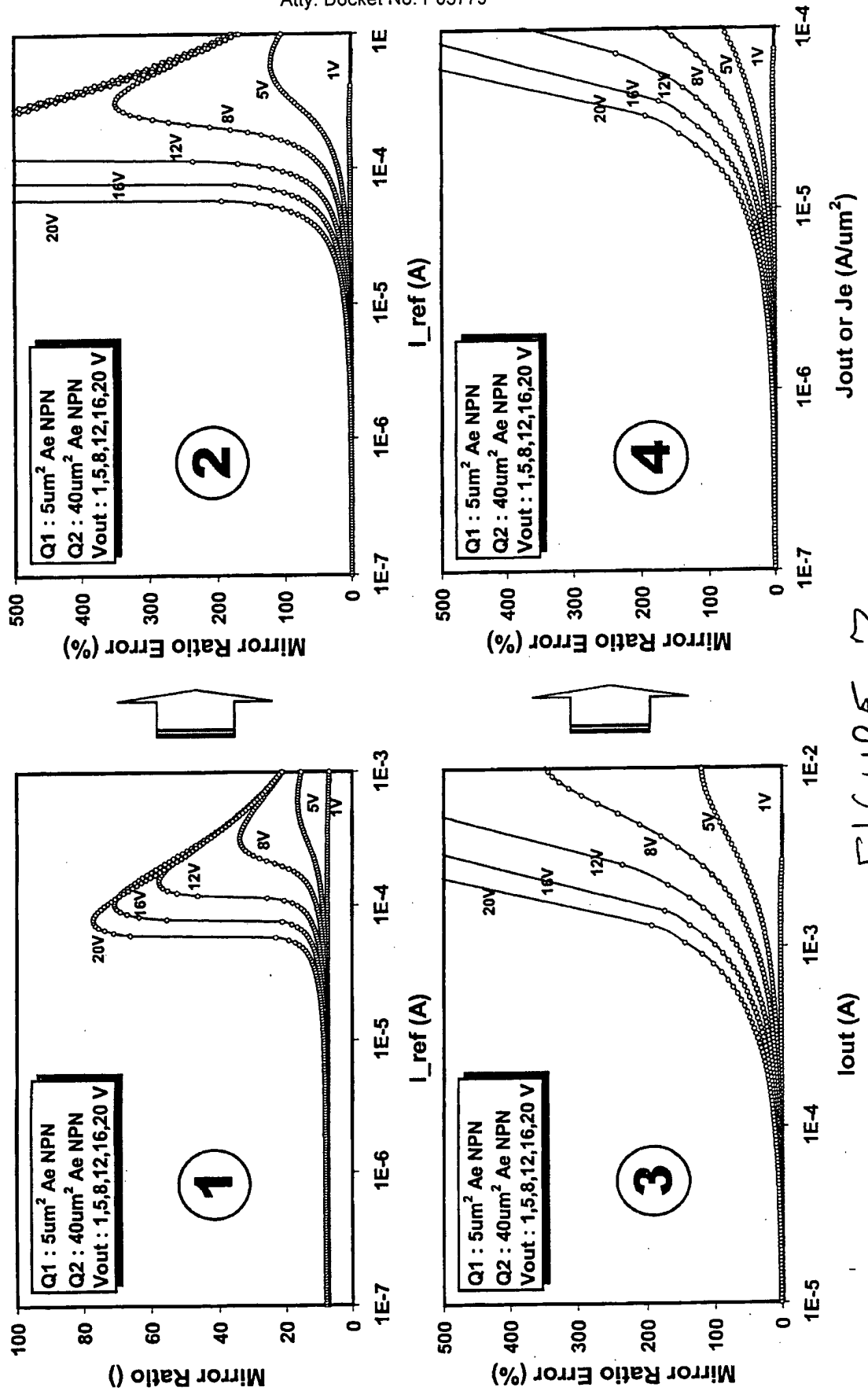


FIGURE 7

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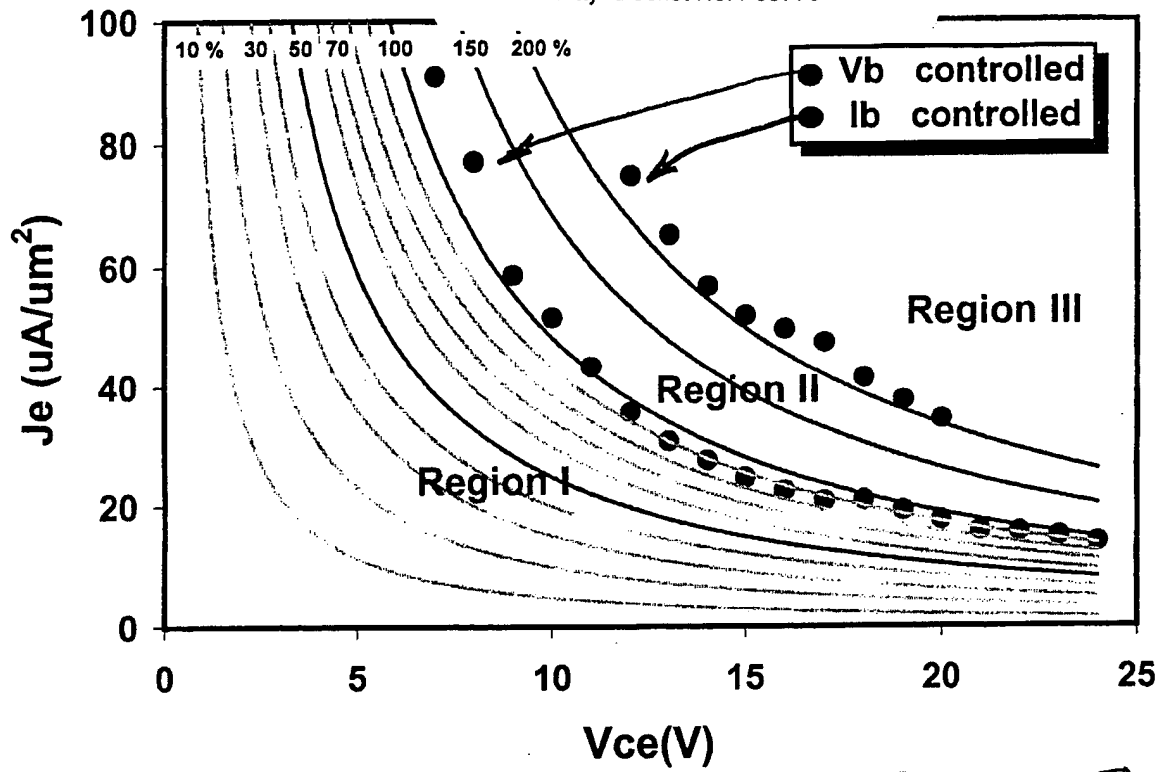


FIGURE 8

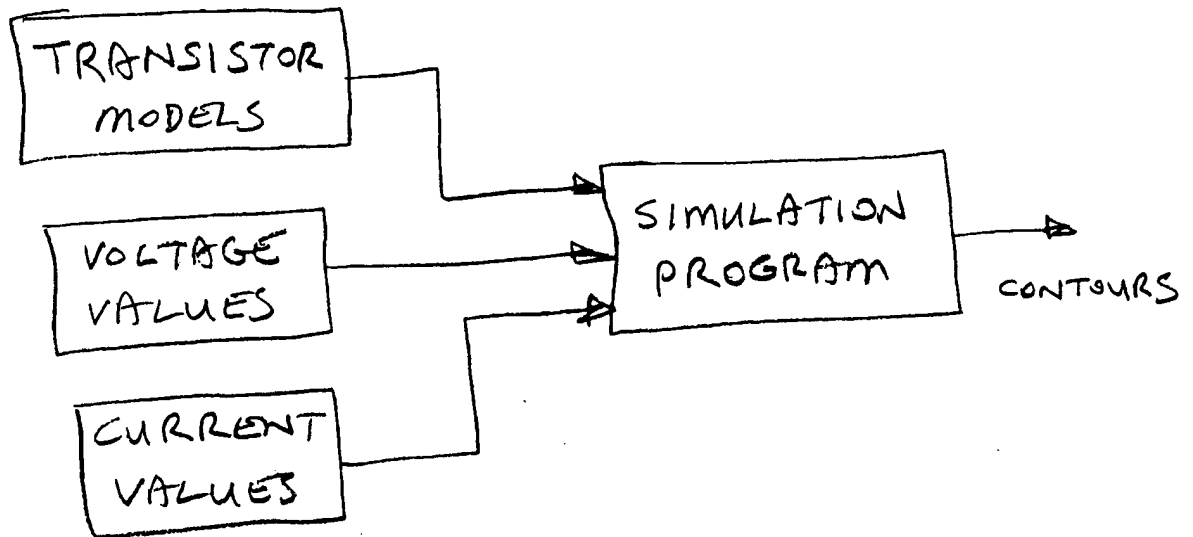


FIGURE 9